

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	1	"5048019".pn.	USPAT	OR	OFF	2005/08/17 08:24
L2	1	"5048019".pn. and (nonvolatile memory operable store test data used testing performed operation other)	USPAT	OR	ON	2005/08/17 09:19
L3	0	"5048019".pn. and (nonvolatile same memory same operable same store same test same data same used same testing same performed same operation same other)	USPAT	OR	ON	2005/08/17 08:08
L4	0	"5048019".pn. and (nonvolatile same memory same operable same store same test same data same testing same performed same operation)	USPAT	OR	ON	2005/08/17 08:06
L5	0	"5048019".pn. and ((nonvolatile adj memory) same store same (test adj data) same testing same performed same operation)	USPAT	OR	ON	2005/08/17 08:06
L6	1	"5048019".pn. and ((nonvolatile adj memory) store (test adj data) testing performed operation)	USPAT	OR	ON	2005/08/17 08:07
L7	0	((test testing) with (nonvolatile adj (memory ((microcomputer microprocessor processor computer) adj (memory register storage))) adj (chip die wafer specimen))) and ((nonvolatile adj memory) same operable same store same (test adj data) same used same testing same performed same operation)	USPAT	OR	ON	2005/08/17 08:14
L8	0	((test testing) with (nonvolatile adj (memory ((microcomputer microprocessor processor computer) adj (memory register storage))) adj (chip die wafer specimen))) and ((nonvolatile adj memory) same operable same store same (test adj data) same used same testing same performed same operation)	US-PGPUB	OR	ON	2005/08/17 08:14
L9	0	((test testing) with (nonvolatile adj (memory ((microcomputer microprocessor processor computer) adj (memory register storage))) adj (chip die wafer specimen))) and ((nonvolatile adj memory) same operable same store same (test adj data) same used same testing same performed same operation)	USOCR	OR	ON	2005/08/17 08:15
L10	0	((test testing) with (nonvolatile adj (memory ((microcomputer microprocessor processor computer) adj (memory register storage))) adj (chip die wafer specimen))) and ((nonvolatile adj memory) same operable same store same (test adj data) same used same testing same performed same operation)	EPO; JPO; DERWENT	OR	ON	2005/08/17 08:15

L11	0	((test testing) with (nonvolatile adj (memory ((microcomputer microprocessor processor computer) adj (memory register storage))) adj (chip die wafer specimen))) and ((nonvolatile adj memory) same operable same store same (test adj data) same used same testing same performed same operation)	IBM_TDB	OR	ON	2005/08/17 08:17
L12	0	((test testing) with (nonvolatile adj (memory ((microcomputer microprocessor processor computer) adj (memory register storage))) rom prom eprom eeprom flash (flash adj (memory register storage))) adj (chip die wafer specimen)) and ((nonvolatile adj memory) same operable same store same (test adj data) same used same testing same performed same operation)	IBM_TDB	OR	ON	2005/08/17 08:20
L13	0	((test testing) with (nonvolatile adj (memory ((microcomputer microprocessor processor computer) adj (memory register storage))) rom prom eprom eeprom flash (flash adj (memory register storage))) adj (chip die wafer specimen)) and ((nonvolatile adj memory) same (operable with store with (test adj data)) same (testing same performed with operation))	IBM_TDB	OR	ON	2005/08/17 08:21
L14	1	((test testing) with (nonvolatile adj (memory ((microcomputer microprocessor processor computer) adj (memory register storage))) rom prom eprom eeprom flash (flash adj (memory register storage))) adj (chip die wafer specimen))	IBM_TDB	OR	ON	2005/08/17 08:25
L15	672	714/736.ccls.	US-PGPUB; USPAT	OR	OFF	2005/08/17 08:24
L16	787	714/733.ccls.	US-PGPUB; USPAT	OR	OFF	2005/08/17 08:25
L17	1013	714/25.ccls.	US-PGPUB; USPAT	OR	OFF	2005/08/17 08:28
L18	842	714/48.ccls.	US-PGPUB; USPAT	OR	OFF	2005/08/17 08:25
L19	1478	714/724.ccls.	US-PGPUB; USPAT	OR	OFF	2005/08/17 08:25
L20	817	714/726.ccls.	US-PGPUB; USPAT	OR	OFF	2005/08/17 08:25
L21	387	714/1.ccls.	US-PGPUB; USPAT	OR	OFF	2005/08/17 08:28
L22	0	714/1.ccls. and ((test testing) with (nonvolatile adj (memory ((microcomputer microprocessor processor computer) adj (memory register storage))) rom prom eprom eeprom flash (flash adj (memory register storage))) adj (chip die wafer specimen))	US-PGPUB; USPAT	OR	ON	2005/08/17 08:29

L23	0	714/25.ccls. and ((test testing) with (nonvolatile adj (memory ((microcomputer microprocessor processor computer) adj (memory register storage))) rom prom eeprom flash (flash adj (memory register storage))) adj (chip die wafer specimen))	US-PGPUB; USPAT	OR	ON	2005/08/17 08:29
L24	0	714/48.ccls. and ((test testing) with (nonvolatile adj (memory ((microcomputer microprocessor processor computer) adj (memory register storage))) rom prom eeprom flash (flash adj (memory register storage))) adj (chip die wafer specimen))	US-PGPUB; USPAT	OR	ON	2005/08/17 08:29
L25	2	714/724.ccls. and ((test testing) with (nonvolatile adj (memory ((microcomputer microprocessor processor computer) adj (memory register storage))) rom prom eeprom flash (flash adj (memory register storage))) adj (chip die wafer specimen))	US-PGPUB; USPAT	OR	ON	2005/08/17 08:29
L26	1	714/726.ccls. and ((test testing) with (nonvolatile adj (memory ((microcomputer microprocessor processor computer) adj (memory register storage))) rom prom eeprom flash (flash adj (memory register storage))) adj (chip die wafer specimen))	US-PGPUB; USPAT	OR	ON	2005/08/17 08:30
L27	8	714/733.ccls. and ((test testing) with (nonvolatile adj (memory ((microcomputer microprocessor processor computer) adj (memory register storage))) rom prom eeprom flash (flash adj (memory register storage))) adj (chip die wafer specimen))	US-PGPUB; USPAT	OR	ON	2005/08/17 08:30
L28	2	714/736.ccls. and ((test testing) with (nonvolatile adj (memory ((microcomputer microprocessor processor computer) adj (memory register storage))) rom prom eeprom flash (flash adj (memory register storage))) adj (chip die wafer specimen))	US-PGPUB; USPAT	OR	ON	2005/08/17 09:18
L29	20	702/108.ccls. and (115 116 117 118 119 120 121)	US-PGPUB; USPAT	OR	OFF	2005/08/17 08:59
L30	77	702/117.ccls. and (115 116 117 118 119 120 121)	US-PGPUB; USPAT	OR	OFF	2005/08/17 08:59
L31	40	702/118.ccls. and (115 116 117 118 119 120 121)	US-PGPUB; USPAT	OR	OFF	2005/08/17 08:59
L32	0	(129 130 131) and ((test testing) with (nonvolatile adj (memory ((microcomputer microprocessor processor computer) adj (memory register storage))) rom prom eeprom flash (flash adj (memory register storage))) adj (chip die wafer specimen))	US-PGPUB; USPAT	OR	ON	2005/08/17 09:00

L33	0	(I29 I30 I31) and ((test testing) same (nonvolatile adj (memory ((microcomputer microprocessor processor computer) adj (memory register storage))) rom prom eprom eeprom flash (flash adj (memory register storage))) adj (chip die wafer specimen))	US-PGPUB; USPAT	OR	ON	2005/08/17 09:00
L34	23	(I29 I30 I31) and ((test testing) same (nonvolatile adj (memory ((microcomputer microprocessor processor computer) adj (memory register storage))) rom prom eprom eeprom flash (flash adj (memory register storage)))	US-PGPUB; USPAT	OR	ON	2005/08/17 09:01
L35	16	(I29 I30 I31) and ((test testing) with (nonvolatile adj (memory ((microcomputer microprocessor processor computer) adj (memory register storage))) rom prom eprom eeprom flash (flash adj (memory register storage)))	US-PGPUB; USPAT	OR	ON	2005/08/17 09:01
L36	1	"20040153924".pn.	US-PGPUB	OR	OFF	2005/08/17 09:18
L37	0	L36 and ((test testing) with (nonvolatile adj (memory ((microcomputer microprocessor processor computer) adj (memory register storage))) rom prom eprom eeprom flash (flash adj (memory register storage))) adj (chip die wafer specimen))	US-PGPUB	OR	ON	2005/08/17 09:18
L38	1	L36 and (nonvolatile memory operable store test data used testing performed operation other)	US-PGPUB	OR	ON	2005/08/17 09:19
L39	0	L36 and ((nonvolatile adj (memory register storage)) same ((operable operative capable capability) with (store storage storing save saving) with (test adj (data information program application routine software firmware)) same (operation adj (data information))))	US-PGPUB	OR	ON	2005/08/17 09:25
L40	0	L36 and ((nonvolatile adj (memory register storage)) same (operable operative capable capability) same (store storage storing save saving) same (test adj (data information program application routine software firmware)) same (operation adj (data information))))	US-PGPUB	OR	ON	2005/08/17 09:26
L41	0	((nonvolatile adj (memory register storage)) same (operable operative capable capability) same (store storage storing save saving) same (test adj (data information program application routine software firmware)) same (operation adj (data information))))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/08/17 09:27
L42	2	((nonvolatile adj (memory register storage)) same (test adj (data information program application routine software firmware)) same (operation adj (data information))))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/08/17 09:27